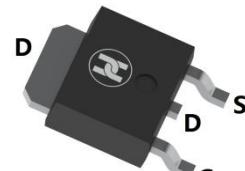


N-CHANNEL HIGH VOLTAGE MOSFET

FEATURES

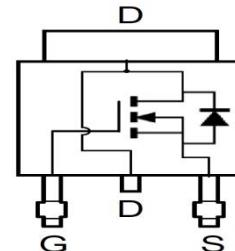
- $R_{DS(ON)} = 11.5\Omega @ V_{GS} = 10V$.
- Ultra Low gate charge (typical 5.0nC)
- Low reverse transfer capacitance ($C_{RSS} = \text{typical } 3.0 \text{ pF}$)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability, high ruggedness



TO-252

MECHANICAL DATA

- Case: TO-252
- Case Material: Molded Plastic. UL flammability
- Classification Rating: 94V-0
- Weight: 0.33 grams (approximate)



MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage	1N60	V_{DSS}	600	V
	1N65		650	V
Gate-Source Voltage		V_{GSS}	± 30	V
Avalanche Current (Note 1)		I_{AR}	1.0	A
Continuous Drain Current		I_D	1.0	A
Pulsed Drain Current (Note 1)		I_{DM}	4.8	A
Avalanche Energy	Single Pulsed (Note 2)	E_{AS}	50	mJ
	Repetitive (Note 1)	E_{AR}	4.0	mJ
Peak Diode Recovery dv/dt (Note 3)		dv/dt	4.5	V/ns
Power Dissipation		P_D	28	W
Junction Temperature		T_J	+150	$^\circ\text{C}$
Operating Temperature		T_{OPR}	-55 ~ +150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55 ~ +150	$^\circ\text{C}$
Junction-to-Ambient		$R_{\theta JA}$	110	$^\circ\text{C}/\text{W}$
Junction-to-Case		$R_{\theta JC}$	4.53	$^\circ\text{C}/\text{W}$

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged.
Absolute maximum ratings are stress ratings only and functional device operation is not implied.

N-CHANNEL HIGH VOLTAGE MOSFET
ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ C$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	1N60 1N65	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	600		V
				650		V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=600V, V_{GS}=0V$		10		μA
Gate-Source Leakage Current	Forward	I_{GSS}	$V_{GS}=30V, V_{DS}=0V$		100	nA
	Reverse		$V_{GS}=-30V, V_{DS}=0V$		-100	nA
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_J$	$I_D=250\mu A$		0.4		$V/^\circ C$
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=0.5A$		9.3	11.5	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{ISS}	$V_{DS}=25V, V_{GS}=0V, f=1MHz$		120	150	pF
Output Capacitance	C_{OSS}			20	25	pF
Reverse Transfer Capacitance	C_{RSS}			3.0	4.0	pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	$t_{D(ON)}$	$V_{DD}=300V, I_D=1.0A, R_G=50\Omega$ (Note 4,5)		5	20	ns
Turn-On Rise Time	t_R			25	60	ns
Turn-Off Delay Time	$t_{D(OFF)}$			7	25	ns
Turn-Off Fall Time	t_F			25	60	ns
Total Gate Charge	Q_G	$V_{DS}=480V, V_{GS}=10V, I_D=1.0A$ (Note 4,5)		5.0	6.0	nC
Gate-Source Charge	Q_{GS}			1.0		nC
Gate-Drain Charge	Q_{GD}			2.6		nC
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_S = 1.0A$			1.4	V
Maximum Continuous Drain-Source Diode Forward Current	I_S				1.2	A
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}				4.8	A
Reverse Recovery Time	t_{RR}	$V_{GS}=0V, I_S=1.0A$ $dI_F/dt=100A/\mu s$ (Note1)		160		ns
Reverse Recovery Charge	Q_{RR}			0.3		μC

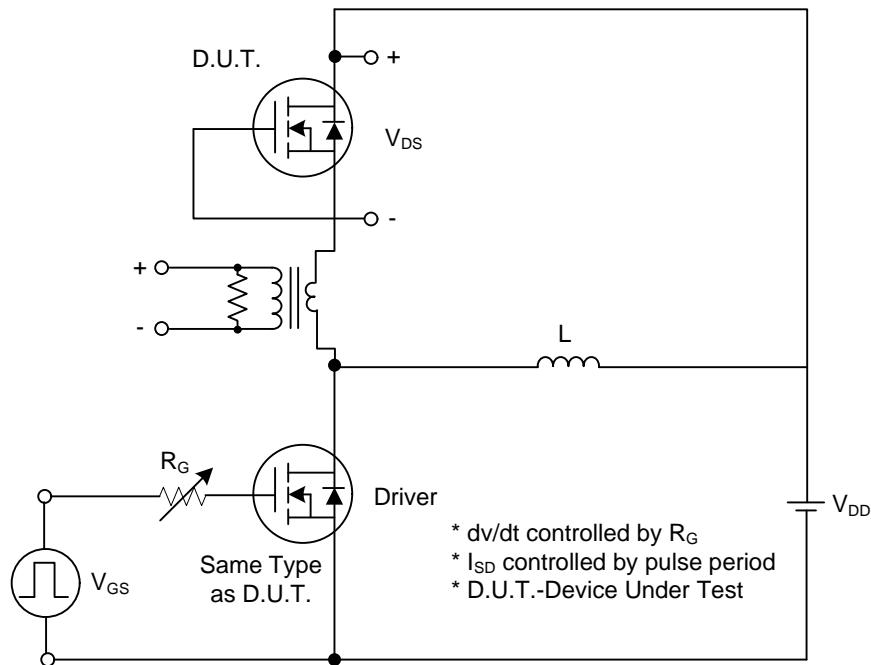
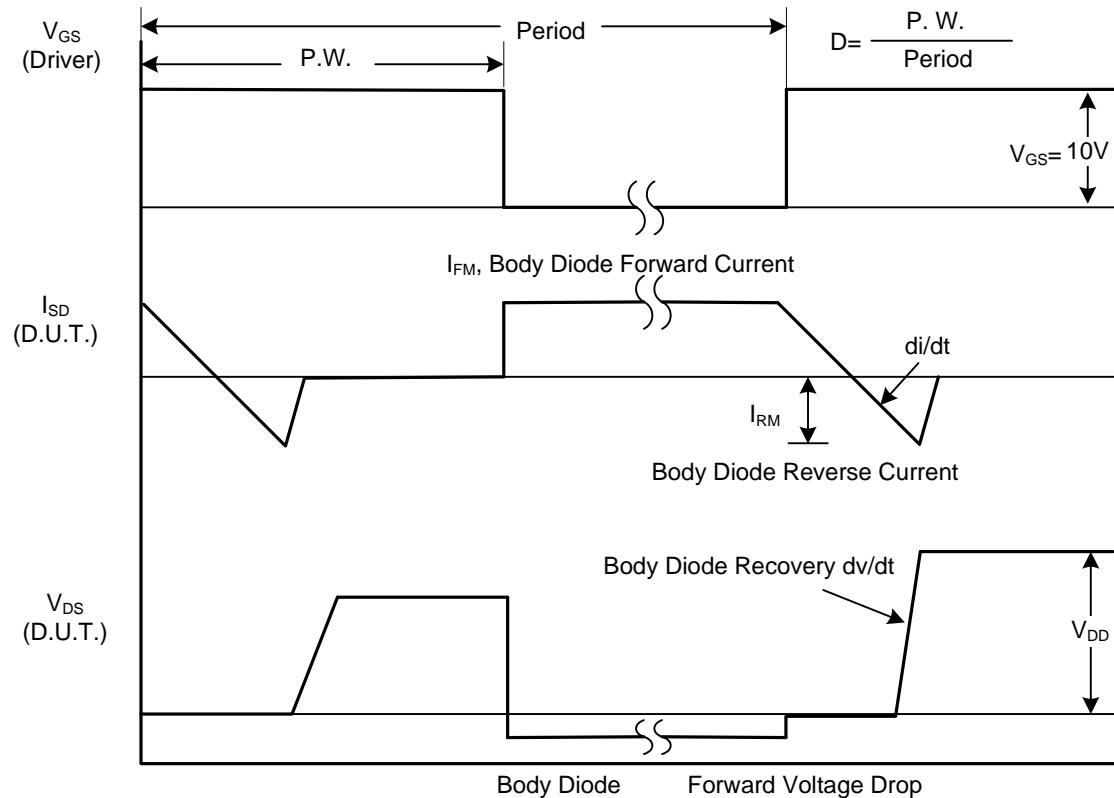
Note: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

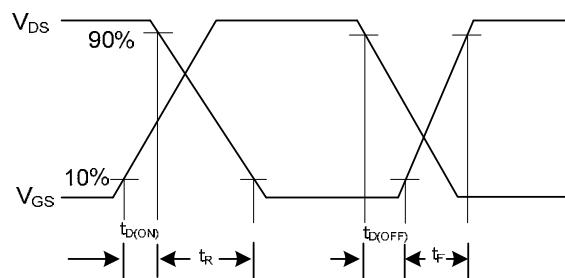
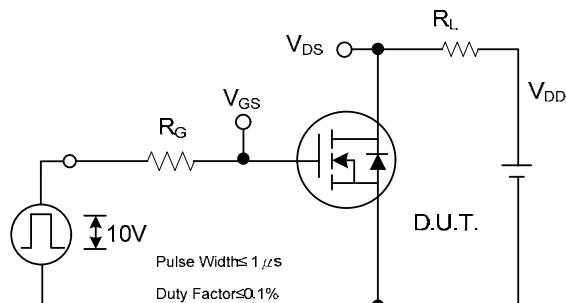
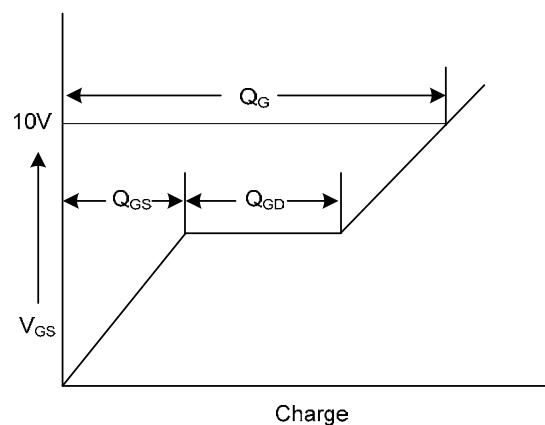
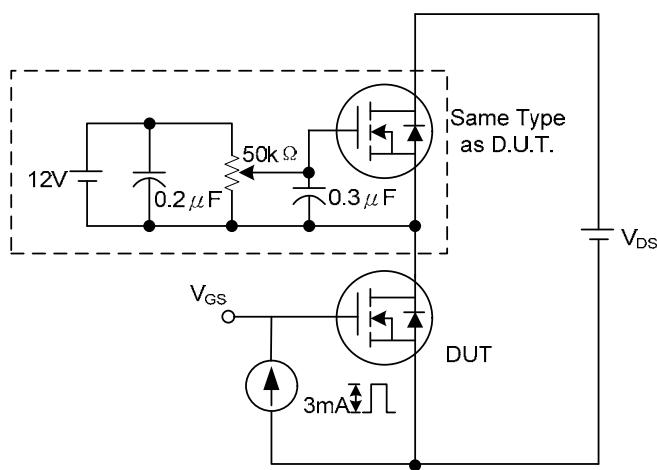
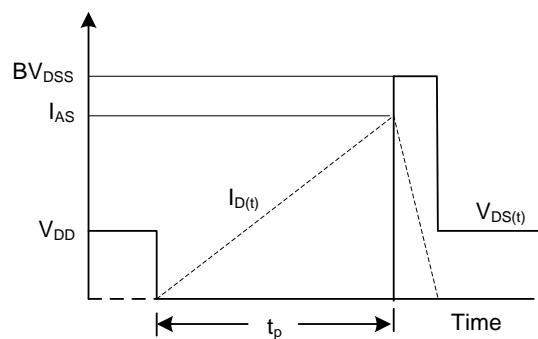
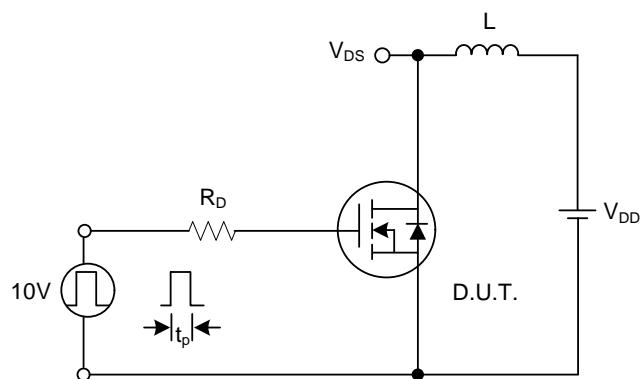
2. $L = 60mH, I_{AS} = 1A, V_{DD} = 50V, R_G = 25\Omega$, Starting $T_J = 25^\circ C$

3. $I_{SD} \leq 1.0A, di/dt \leq 200A/\mu s, V_{DD} \leq BV_{DSS}$, Starting $T_J = 25^\circ C$

4. Pulse Test: Pulse Width $\leq 300\mu s$, Duty Cycle $\leq 2\%$

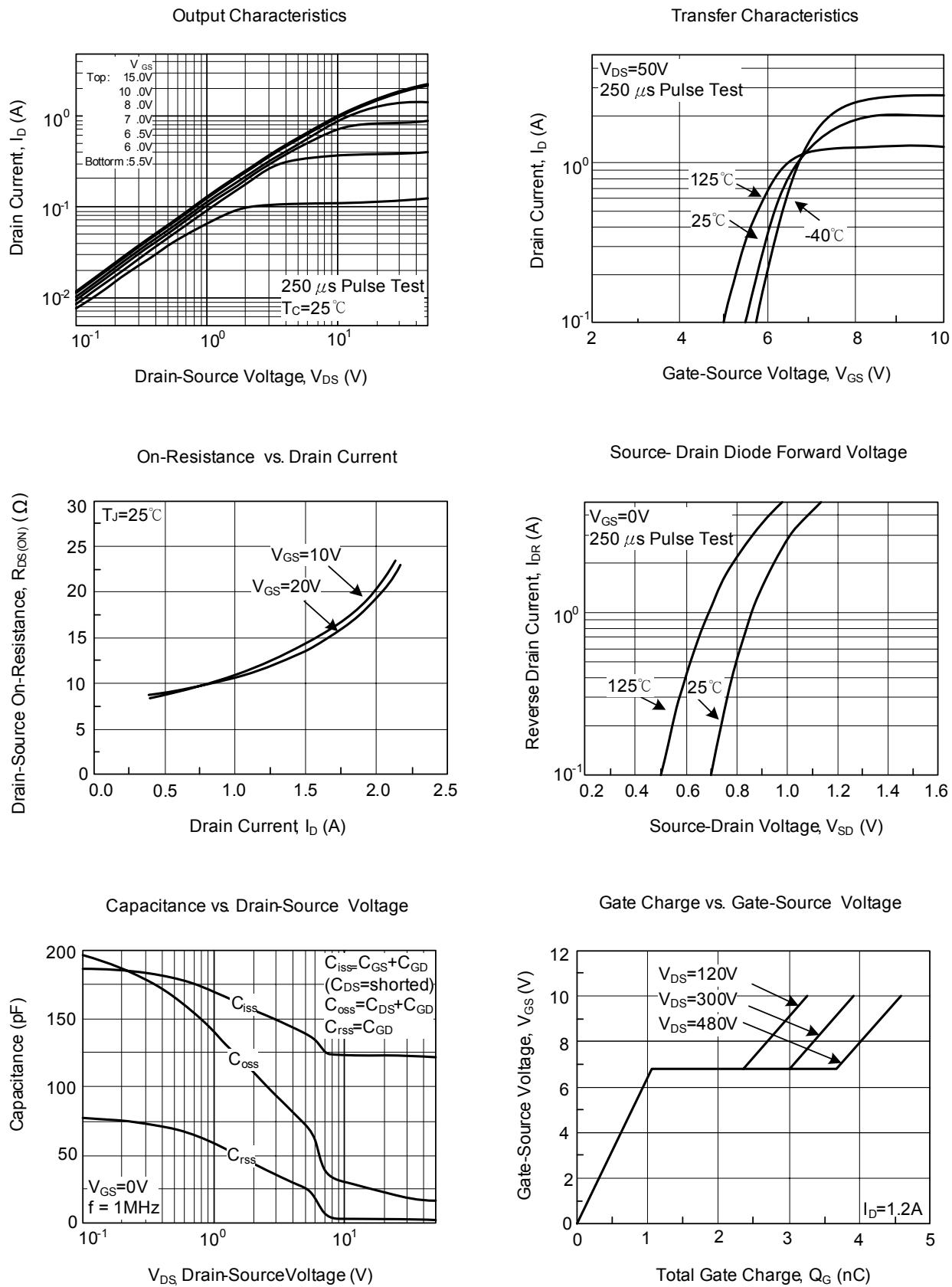
5. Essentially Independent of Operating Temperature

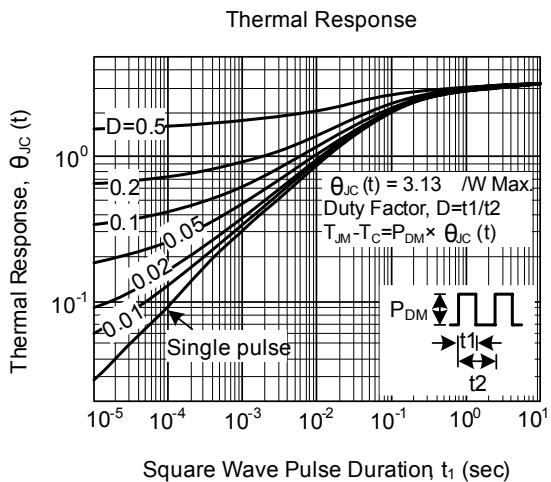
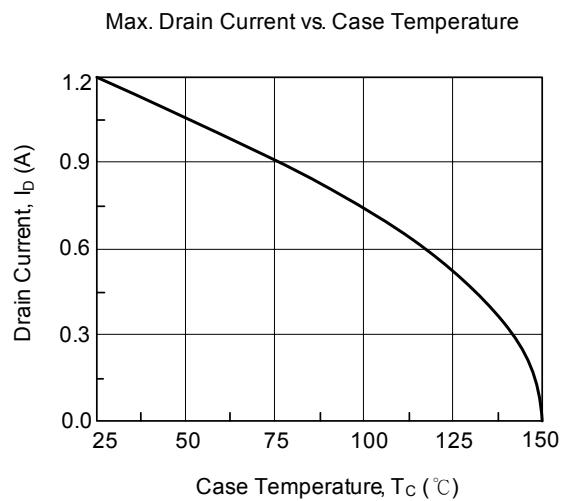
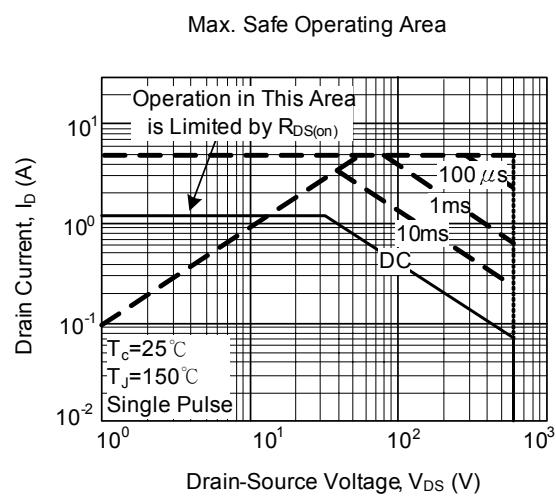
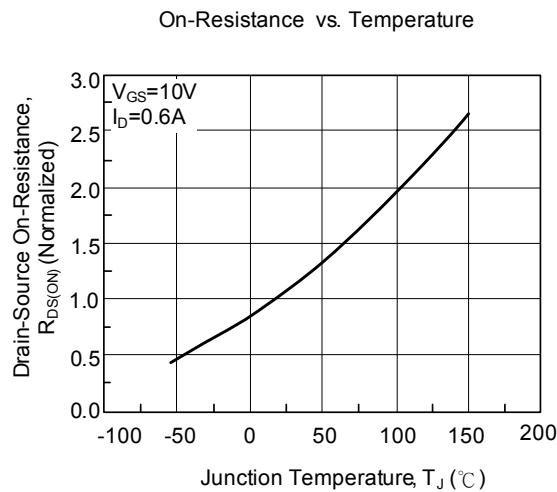
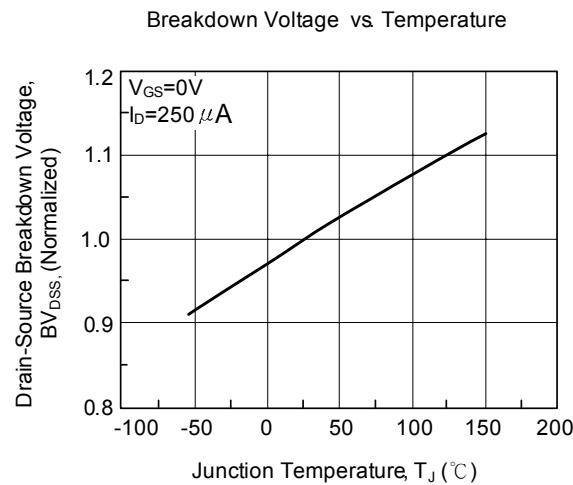
N-CHANNEL HIGH VOLTAGE MOSFET
Test Circuits and Waveforms

Fig. 1A Peak Diode Recovery dv/dt Test Circuit

Fig. 1B Peak Diode Recovery dv/dt Waveforms

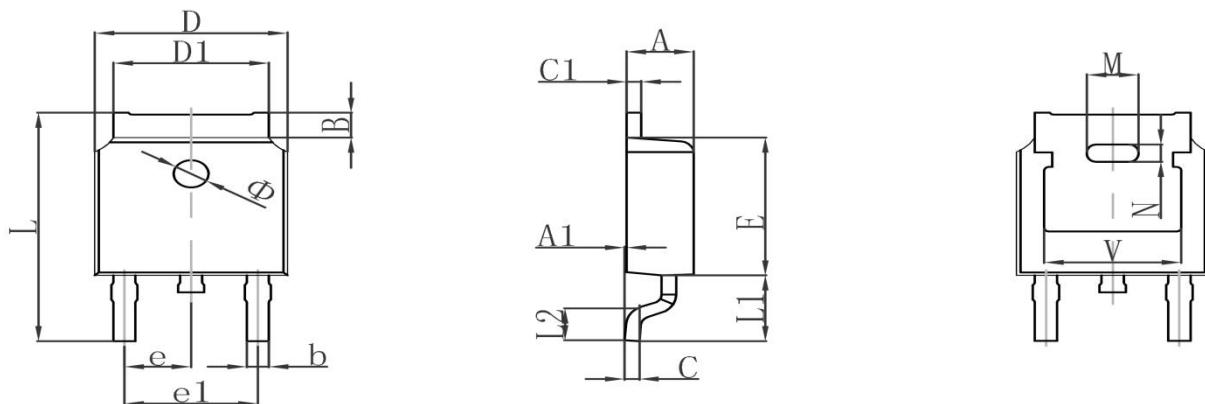
N-CHANNEL HIGH VOLTAGE MOSFET

Fig. 2A Switching Test Circuit
Fig. 2B Switching Waveforms

Fig. 3A Gate Charge Test Circuit
Fig. 3B Gate Charge Waveform

Fig. 4A Unclamped Inductive Switching Test Circuit
Fig. 4B Unclamped Inductive Switching Waveforms

N-CHANNEL HIGH VOLTAGE MOSFET

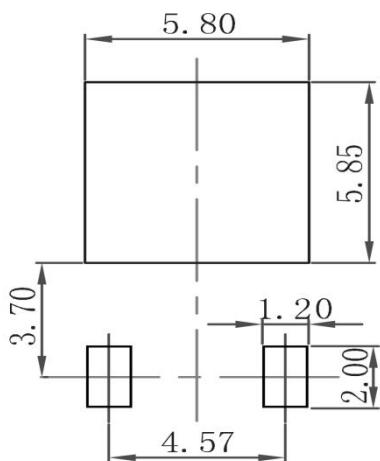
Typical Characteristics



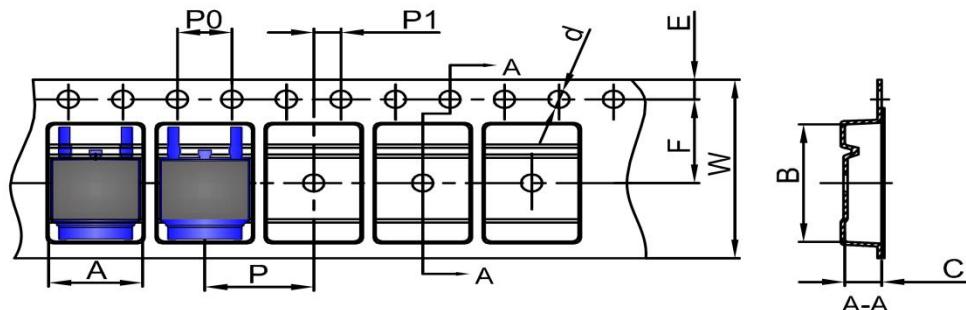
N-CHANNEL HIGH VOLTAGE MOSFET


N-CHANNEL HIGH VOLTAGE MOSFET
TO-252 Package Outline Dimensions


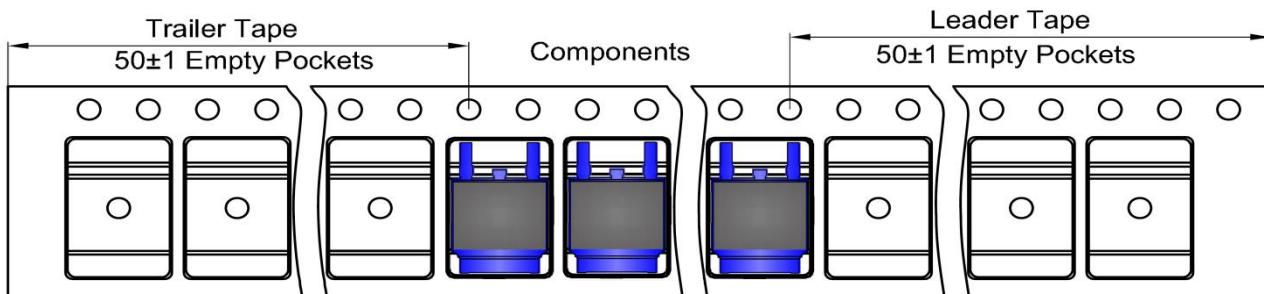
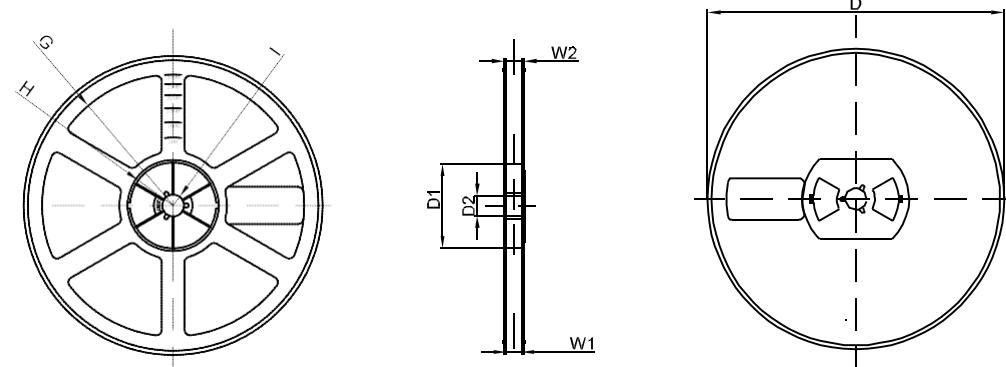
Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.380	0.087	0.094
A1	0.000	0.100	0.000	0.004
B	0.800	1.400	0.031	0.055
b	0.710	0.810	0.028	0.032
c	0.460	0.560	0.018	0.022
c1	0.460	0.560	0.018	0.022
D	6.500	6.700	0.256	0.264
D1	5.130	5.460	0.202	0.215
E	6.000	6.200	0.236	0.244
e	2.286TYP		0.090TYP	
e1	4.327	4.727	0.170	0.186
M	1.778REF		0.070REF	
N	0.762REF		0.018REF	
L	9.800	10.400	0.386	0.409
L1	2.9REF		0.114REF	
L2	1.400	1.700	0.055	0.067
V	4.830REF		0.190REF	
Φ	1.100	1.300	0.043	0.051

TO-252 Suggested Pad Layout

Note:

1. Controlling dimension: in millimeters
2. General tolerance: $\pm 0.05\text{mm}$
3. The pad layout is for reference purposes only

N-CHANNEL HIGH VOLTAGE MOSFET
TO-252 Tape and Reel
TO-252 Embossed Carrier Tape


TYPE	DIMENSIONS ARE IN MILLIMETER									
	A	B	C	d	E	F	P0	P	P1	W
TO-252	6.90	10.50	2.70	Ø1.55	1.75	7.50	4.00	8.00	2.00	16.00
TOLERANCE	±0.1	±0.1	±0.1	±0.1	±0.1	±0.1	±0.1	±0.1	±0.1	±0.1

TO-252 Tape Leader and Trailer

TO-252 Reel


REEL OPTION	DIMENSIONS ARE IN MILLIMETER							
	D	D1	D2	G	H	I	W1	W2
13" DIA	Ø330.00	100.00	Φ21.00	R151.00	R56.00	R6.50	16.40	21.00
TOLERANCE	±2	±1	±1	±1	±1	±1	±1	±1